## Notice of References Cited

Application/Control No.

10/665,691

Examiner

Charles Shedrick

Applicant(s)/Patent Under
Reexamination
SIMEK ET AL.

Art Unit
Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,703,932	12-1997	Oda, Teruo	455/566
*	В	US-6,625,283	09-2003	Sato, Hisashi	379/433.07
*	С	US-D497,601	10-2004	Brandis, Michael	D14/138
*	D	US-D469,749	02-2003	Kim, Young S.	D14/138
*	E	US-5,884,185	03-1999	Kim, Jong-Kwang	455/566
*	F	US-2003/0073414	04-2003	P. Capps, Stephen	455/90
*	G	US-2002/0045467 A1	04-2002	Hama, Mitsuji	455/567
*	Н	US-2006/0030375	02-2006	Tanaka, Katsuzo	455/575.1
*	1	US-6,889,064 B2	05-2005	Baratono et al.	455/569.2
*	J	US-5,332,322	07-1994	Gambaro, Thomas L.	400/489
*	κ	US-6,947,028 B2	09-2005	Shkolnikov, Mark	345/156
*	L	US-6,697,639 B2	02-2004	Andress, Scott R.	455/556.1
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP2001-265490	09-2001	Japan	Sony Corp	
*	0	JP2000-151774	05-2000	Japan	Matsushita Electric Ind C	
	P					·
	Q					
	R				·	
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	٧	
	w	
	х	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.